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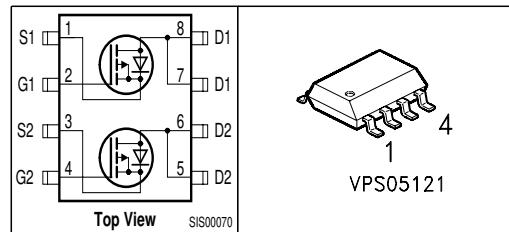
## OptiMOS™-P Power-Transistor

### Feature

- Dual P-Channel
- Enhancement mode
- Logic Level
- 150°C operating temperature
- Avalanche rated
- dv/dt rated

### Product Summary

$V_{DS}$	-30	V
$R_{DS(on)}$	21	$\text{m}\Omega$
$I_D$	-8.2	A



Type	Package
BSO303P	P-SO 8

**Maximum Ratings**, at  $T_j = 25^\circ\text{C}$ , unless otherwise specified

Parameter	Symbol	Value	Unit
Continuous drain current $T_A=25^\circ\text{C}$	$I_D$	-8.2	A
$T_A=70^\circ\text{C}$			
Pulsed drain current $T_A=25^\circ\text{C}$	$I_{D \text{ puls}}$	-32.4	
Avalanche energy, single pulse $I_D=-8.2 \text{ A}, V_{DD}=-25\text{V}, R_{GS}=25\Omega$			
Reverse diode dv/dt $I_S=-8.2\text{A}, V_{DS}=-24\text{V}, dI/dt=200\text{A}/\mu\text{s}, T_{jmax}=150^\circ\text{C}$	$dv/dt$	-6	$\text{kV}/\mu\text{s}$
Gate source voltage	$V_{GS}$	$\pm 20$	V
Power dissipation $T_A=25^\circ\text{C}$	$P_{\text{tot}}$	2	W
Operating and storage temperature	$T_j, T_{stg}$	-55... +150	$^\circ\text{C}$
IEC climatic category; DIN IEC 68-1		55/150/56	

**Thermal Characteristics**

Parameter	Symbol	Values			Unit
		min.	typ.	max.	
<b>Characteristics</b>					
Thermal resistance, junction - soldering point	$R_{\text{thJS}}$	-	-	50	K/W
SMD version, device on PCB: @ min. footprint, $t < 10\text{s}$ @ 6 cm <sup>2</sup> cooling area <sup>1)</sup>	$R_{\text{thJA}}$	-	-	110 62.5	

**Electrical Characteristics**, at  $T_j = 25^\circ\text{C}$ , unless otherwise specified

Parameter	Symbol	Values			Unit
		min.	typ.	max.	
<b>Static Characteristics</b>					
Drain-source breakdown voltage $V_{\text{GS}}=0, I_D=-250\mu\text{A}$	$V_{(\text{BR})\text{DSS}}$	-30	-	-	V
Gate threshold voltage, $V_{\text{GS}} = V_{\text{DS}}$ $I_D=-100\mu\text{A}$	$V_{\text{GS}(\text{th})}$	-1	-1.5	-2	
Zero gate voltage drain current $V_{\text{DS}}=-30\text{V}, V_{\text{GS}}=0, T_j=25^\circ\text{C}$ $V_{\text{DS}}=-30\text{V}, V_{\text{GS}}=0, T_j=150^\circ\text{C}$	$I_{\text{DSS}}$	-	-0.1 -10	-1 -100	$\mu\text{A}$
Gate-source leakage current $V_{\text{GS}}=-20\text{V}, V_{\text{DS}}=0$	$I_{\text{GSS}}$	-	-10	-100	nA
Drain-source on-state resistance $V_{\text{GS}}=-4.5\text{V}, I_D=-6.6\text{A}$	$R_{\text{DS}(\text{on})}$	-	26	32	$\text{m}\Omega$
Drain-source on-state resistance $V_{\text{GS}}=-10\text{V}, I_D=-8.2\text{A}$	$R_{\text{DS}(\text{on})}$	-	18	21	

<sup>1)</sup>Device on 40mm\*40mm\*1.5mm epoxy PCB FR4 with 6cm<sup>2</sup> (one layer, 70 µm thick) copper area for drain connection. PCB is vertical without blown air;  $t \leq 10$  sec.

**Electrical Characteristics**, at  $T_j = 25^\circ\text{C}$ , unless otherwise specified

Parameter	Symbol	Conditions	Values			Unit
			min.	typ.	max.	
<b>Dynamic Characteristics</b>						
Transconductance	$g_{fs}$	$ V_{DS}  \geq 2^*  I_D  * R_{DS(on)max}$ $I_D = -6.6\text{A}$	11	22	-	S
Input capacitance	$C_{iss}$	$V_{GS} = 0, V_{DS} = -25\text{V},$ $f = 1\text{MHz}$	-	1761	-	pF
Output capacitance	$C_{oss}$		-	495	-	
Reverse transfer capacitance	$C_{rss}$		-	410	-	
Turn-on delay time	$t_{d(on)}$	$V_{DD} = -15\text{V}, V_{GS} = -10\text{V},$ $I_D = -1\text{A}, R_G = 6\Omega$	-	10.6	15.9	ns
Rise time	$t_r$		-	12.9	19.3	
Turn-off delay time	$t_{d(off)}$		-	55.4	83.1	
Fall time	$t_f$		-	39.3	59	

### Gate Charge Characteristics

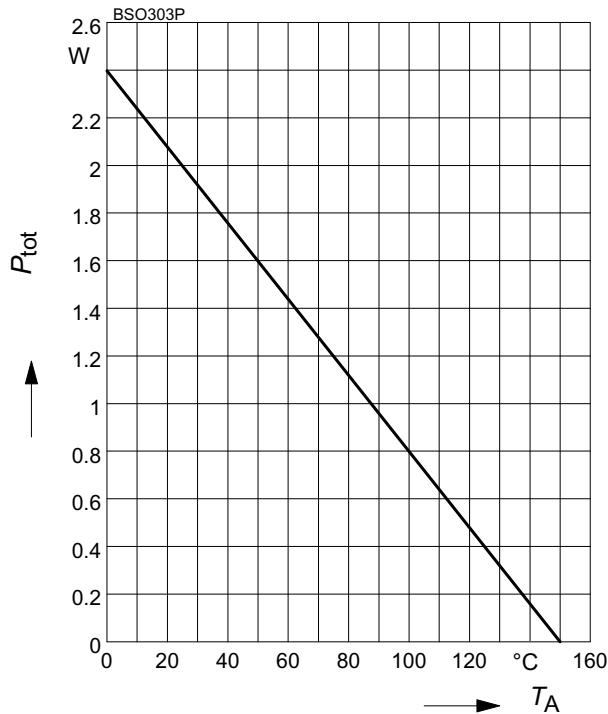
Gate to source charge	$Q_{qs}$	$V_{DD} = -24\text{V}, I_D = -8.2\text{A}$	-	-4.25	-6.4	nC
Gate to drain charge	$Q_{qd}$		-	-15.2	-23	
Gate charge total	$Q_g$	$V_{DD} = -24\text{V}, I_D = -8.2\text{A},$ $V_{GS} = 0 \text{ to } -10\text{V}$	-	-48.3	-72.5	
Gate plateau voltage	$V_{(plateau)}$	$V_{DD} = -24\text{V}, I_D = -8.2\text{A}$	-	-2.4	-	V

### Reverse Diode

Inverse diode continuous forward current	$I_S$	$T_A = 25^\circ\text{C}$	-	-	-2.2	A
Inverse diode direct current, pulsed	$I_{SM}$		-	-	-32.4	
Inverse diode forward voltage	$V_{SD}$	$V_{GS} = 0,  I_F  =  I_D $	-	-0.88	-1.32	
Reverse recovery time	$t_{rr}$	$V_R = -15\text{V},  I_F  =  I_D ,$ $dI_F/dt = 100\text{A}/\mu\text{s}$	-	24.4	36.6	ns
Reverse recovery charge	$Q_{rr}$		-	12.8	19.2	

### 1 Power dissipation

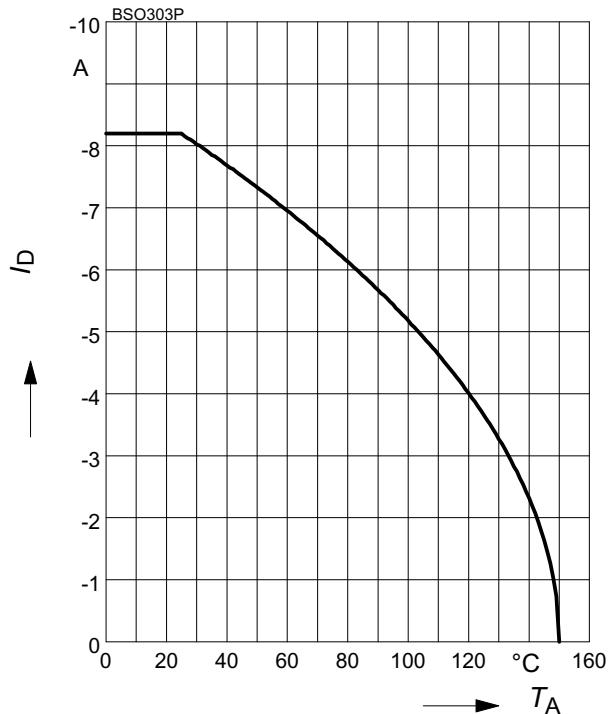
$$P_{\text{tot}} = f(T_A)$$



### 2 Drain current

$$I_D = f(T_A)$$

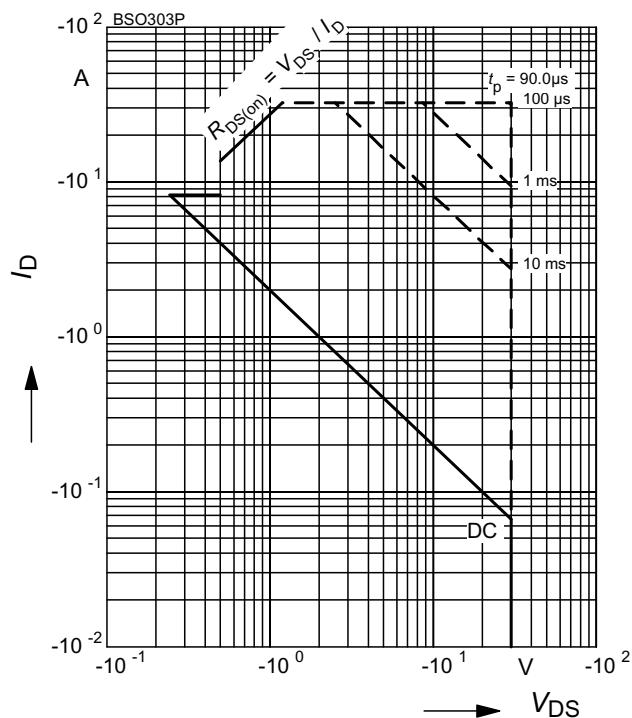
parameter:  $|V_{GS}| \geq 10$  V



### 3 Safe operating area

$$I_D = f(V_{DS})$$

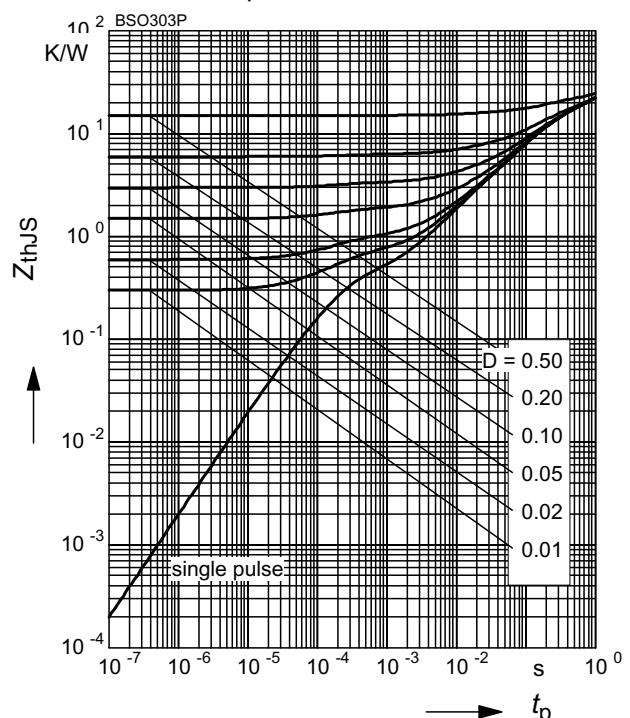
parameter :  $D = 0$  ,  $T_A = 25$  °C



### 4 Transient thermal impedance

$$Z_{\text{thJS}} = f(t_p)$$

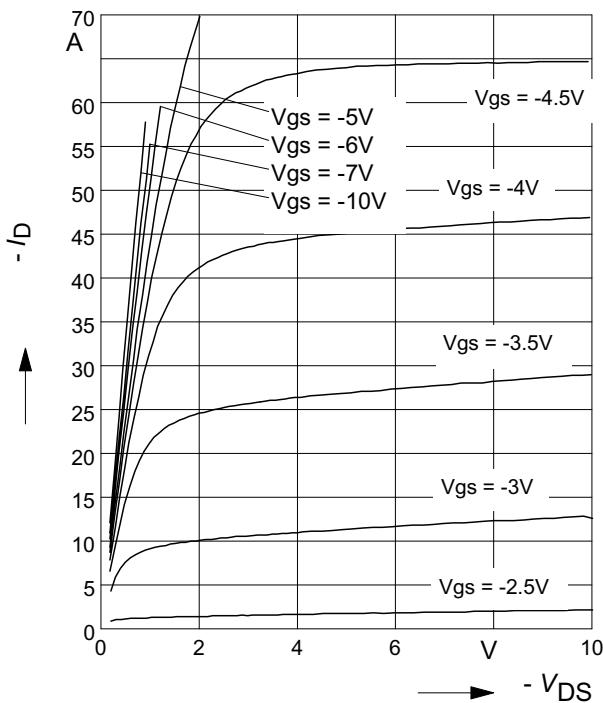
parameter :  $D = t_p/T$



### 5 Typ. output characteristic

$$I_D = f(V_{DS}); T_j=25^\circ\text{C}$$

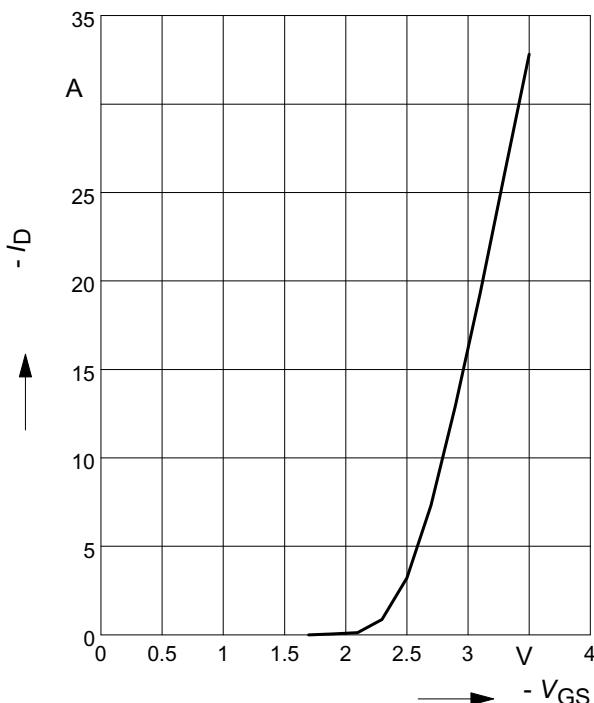
parameter:  $t_p = 80 \mu\text{s}$



### 7 Typ. transfer characteristics

$$I_D = f(V_{GS}); |V_{DS}| \geq 2 \times |I_D| \times R_{DS(on)}\max$$

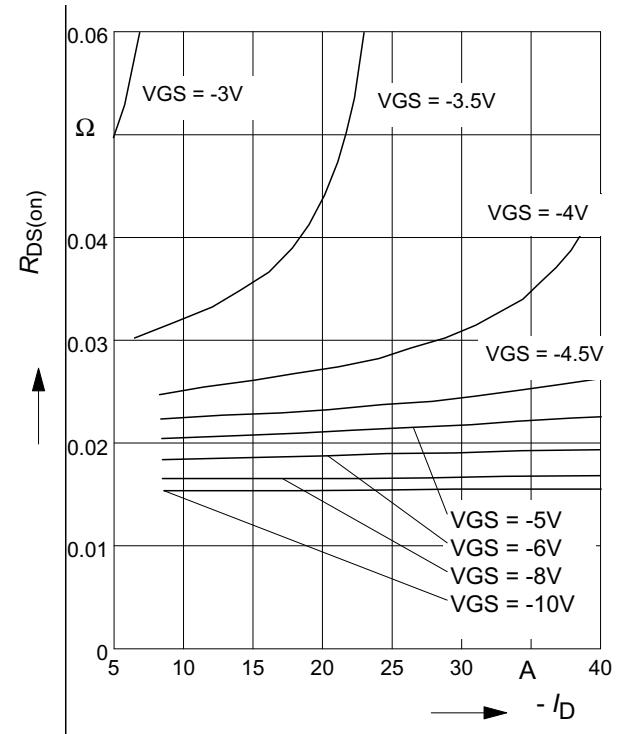
parameter:  $t_p = 80 \mu\text{s}$



### 6 Typ. drain-source on resistance

$$R_{DS(on)} = f(I_D)$$

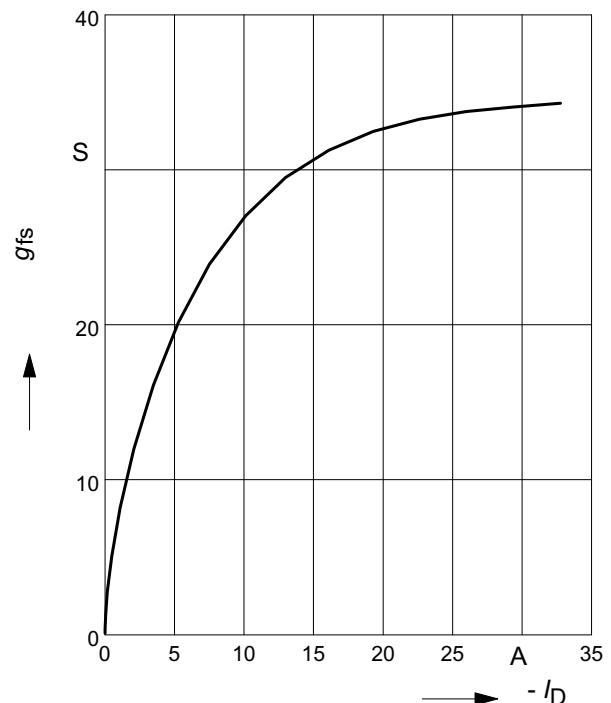
parameter:  $V_{GS}$



### 8 Typ. forward transconductance

$$g_{fs} = f(I_D); T_j=25^\circ\text{C}$$

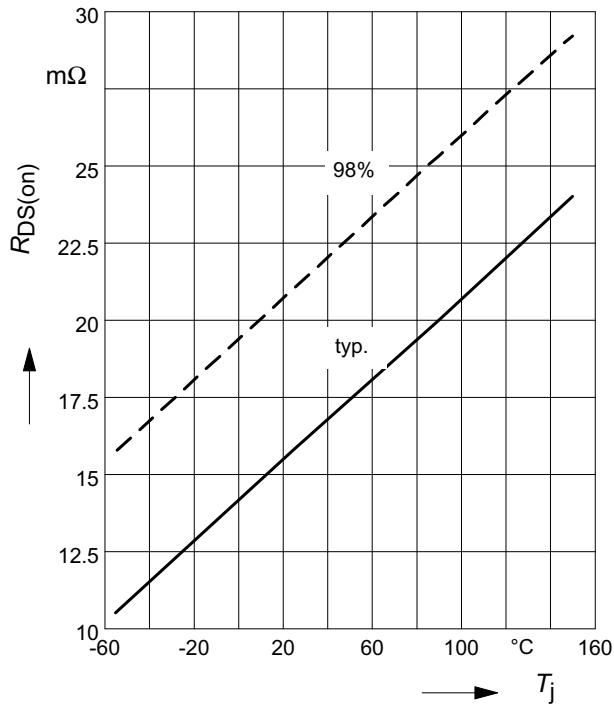
parameter:  $t_p = 80 \mu\text{s}$



### 9 Drain-source on-resistance

$$R_{DS(on)} = f(T_j)$$

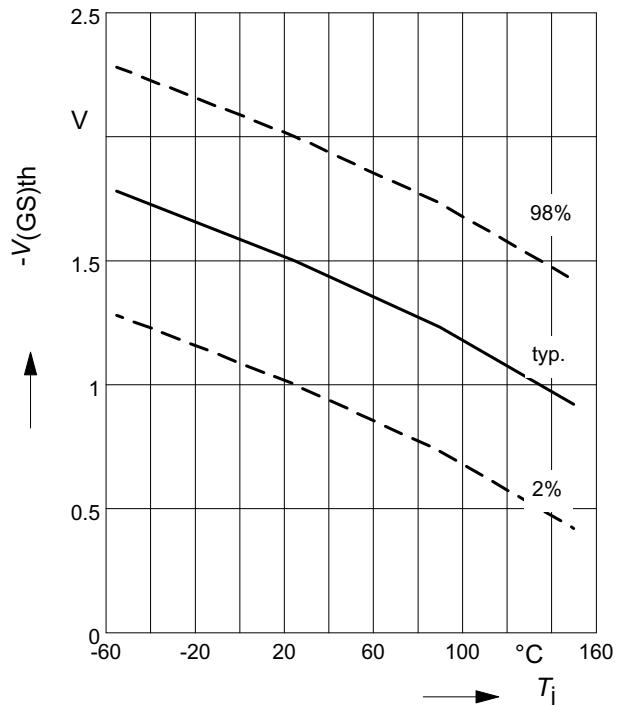
parameter:  $I_D = -8.2 \text{ A}$ ,  $V_{GS} = -10 \text{ V}$



### 10 Typ. gate threshold voltage

$$V_{GS(th)} = f(T_j)$$

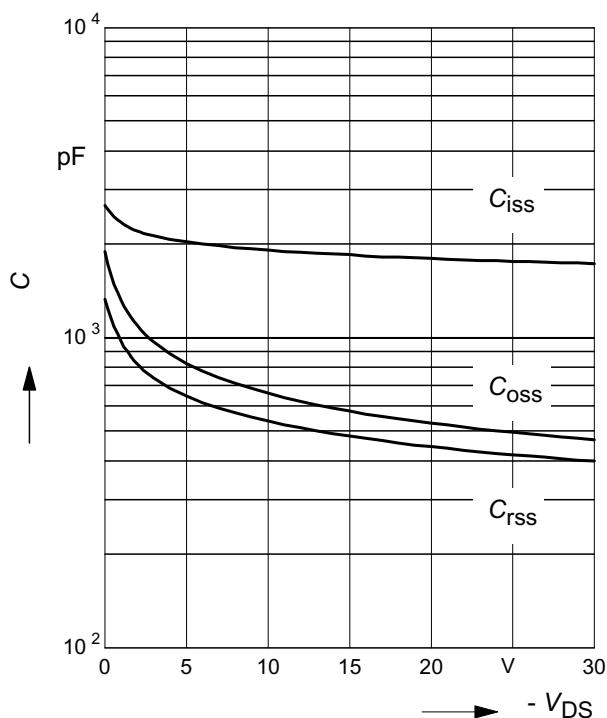
parameter:  $V_{GS} = V_{DS}$



### 11 Typ. capacitances

$$C = f(V_{DS})$$

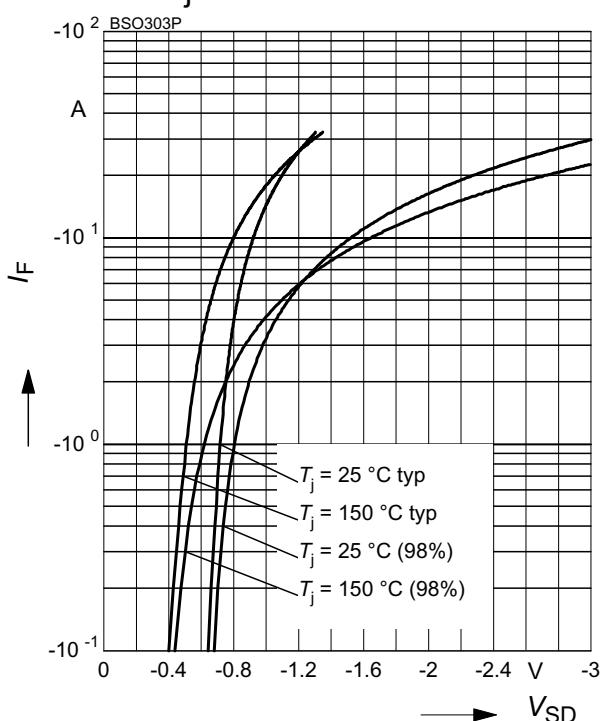
parameter:  $V_{GS}=0$ ,  $f=1 \text{ MHz}$



### 12 Forward character. of reverse diode

$$I_F = f(V_{SD})$$

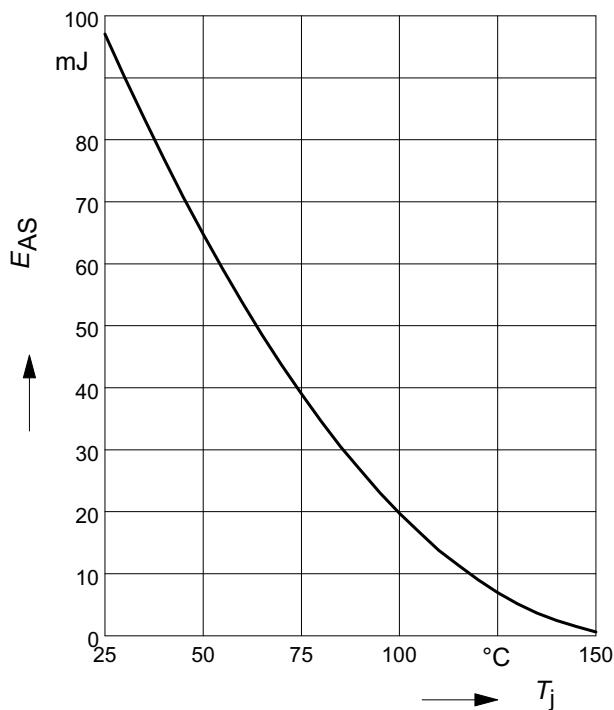
parameter:  $T_j$ ,  $t_p = 80 \mu\text{s}$



### 13 Typ. avalanche energy

$$E_{AS} = f(T_j), \text{ par.: } I_D = -8.2 \text{ A}$$

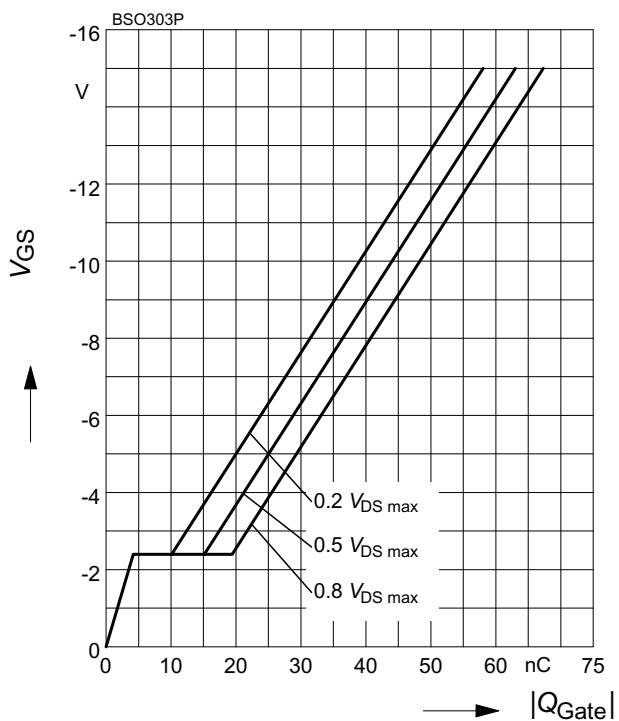
$$V_{DD} = -25 \text{ V}, R_{GS} = 25 \Omega$$



### 14 Typ. gate charge

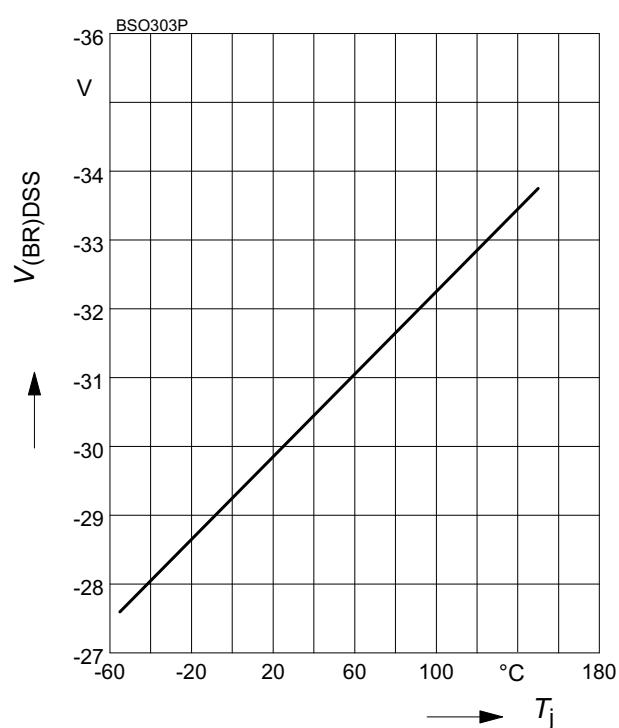
$$V_{GS} = f(Q_{Gate})$$

parameter:  $I_D = -8.2 \text{ A}$  pulsed



### 15 Drain-source breakdown voltage

$$V_{(BR)DSS} = f(T_j)$$



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